

PATENT

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IN THE SPECIFICATION:

Please replace the Abstract with the following amended paragraph:

Methods and systems for reducing the volume of test data associated with built in self testing (BIST) test methodologies (e.g., logical BIST, array BIST, etc.) and pattern structures are provided. ~~Rather than store the entire set of test parameters for each of a plurality of test sequences to be performed, as with conventional test systems, embodiments~~ Embodiments of the present invention ~~only~~ store a limited number of “dynamic” test parameters for each test sequence that have changed relative to a previous test sequence.